

## **relative detection limit**

(Often incorrectly referred to as sensitivity). Smallest amount of material detectable ( $3\sigma$ -criterion) in a matrix relative to the amount of material analysed — given in atomic, mole or weight fractions.

**Source:**

PAC, 1979, 51, 2243 (*General aspects of trace analytical methods - IV. Recommendations for nomenclature, standard procedures and reporting of experimental data for surface analysis techniques*) on page 2247